

# MB81C51-25/-30

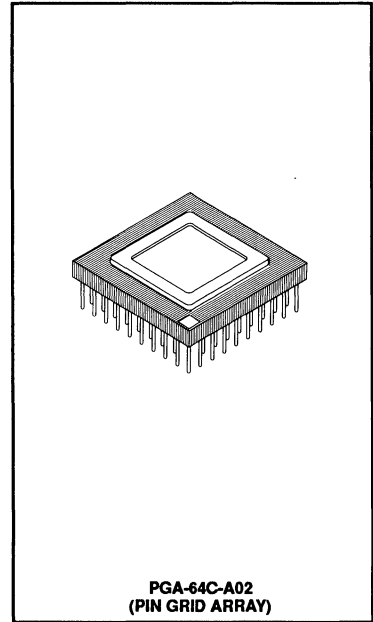
## CMOS TAG RANDOM ACCESS MEMORY

### CMOS Tag Random Access Memory

The Fujitsu MB81C51 is a 512 entry x 4 way or 1024 entry x 2 way tag random access memory (Tag RAM) fabricated with CMOS technology.

The MB81C51 is ideal for use in cache memory systems with other RAMs. This device offers the advantages of compact design and high performance in cache systems for use with 32-bit CPUs.

- Organization: 512 Entry x 4 way or  
1024 Entry x 2 way
- Access time: 30 ns max from Address Inputs  
18 ns max from Compare Data Inputs
- Power consumption: 1375 mW max.
- Single +5 V power supply  $\pm 10\%$  tolerance
- TTL compatible inputs and outputs
- LRU (Least Recently Used) replacement logic
- Purge function (All-purge and partial-purge)
- Internal parity generator/checker
- Standard 64-pin Ceramic Pin Grid Array Package:  
PGA MB81C51-xxCR



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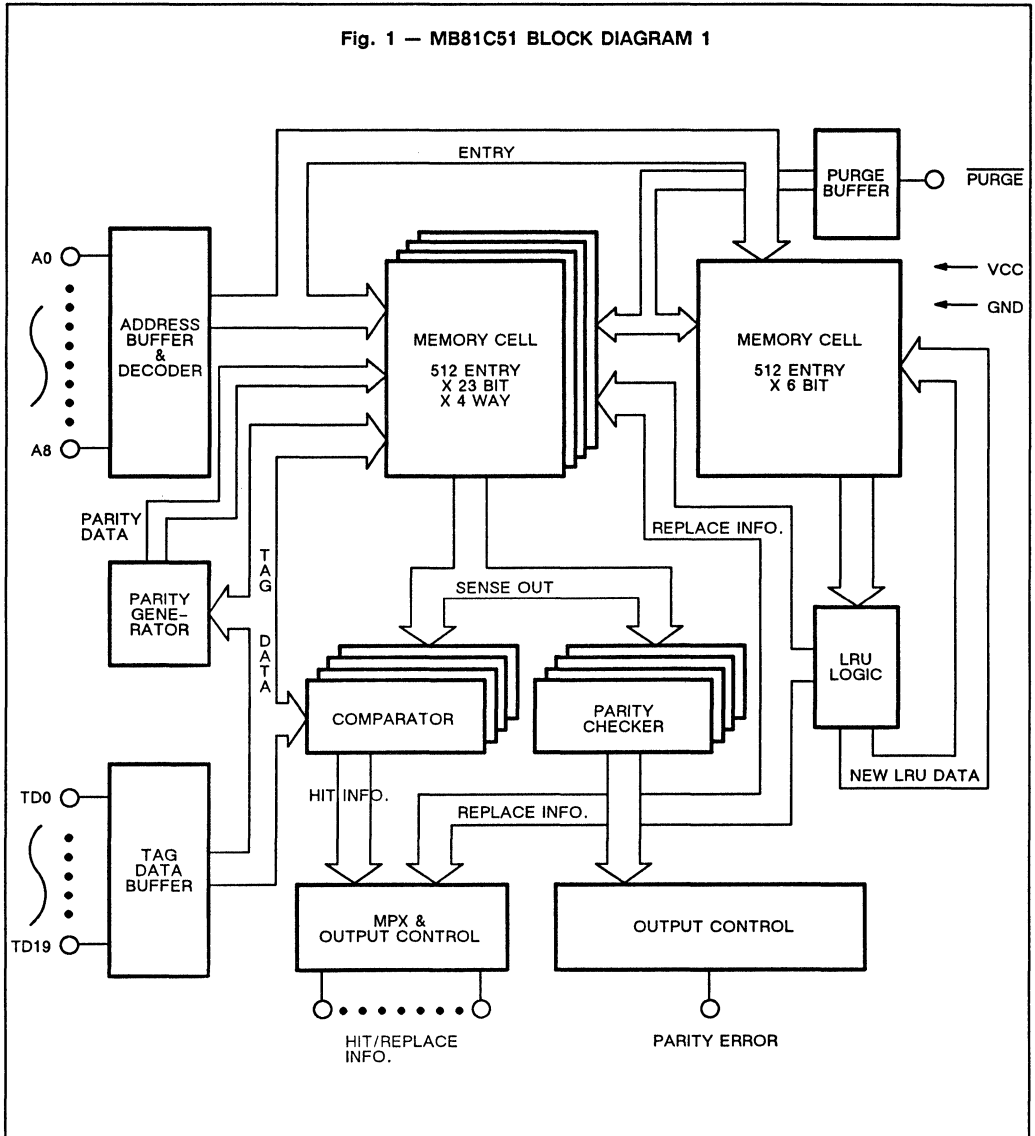
### Absolute Maximum Ratings (See Note)

Rating	Symbol	Value	Unit
Supply Voltage	$V_{CC}$	-0.5 to +7	V
Input Voltage on any pin with respect to GND	$V_{IN}$	-3.0 to +7	V
Output Voltage on any pin with respect to GND	$V_{OUT}$	-0.5 to +7	V
Output Current	$I_{OUT}$	$\pm 20$	mA
Power Dissipation	$P_D$	1.5	W
Temperature Under Bias	$T_{BIAS}$	-10 to +85	$^{\circ}C$
Storage Temperature Range	$T_{STG}$	-65 to +125	$^{\circ}C$

**Note:** Permanent device damage may occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operation sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

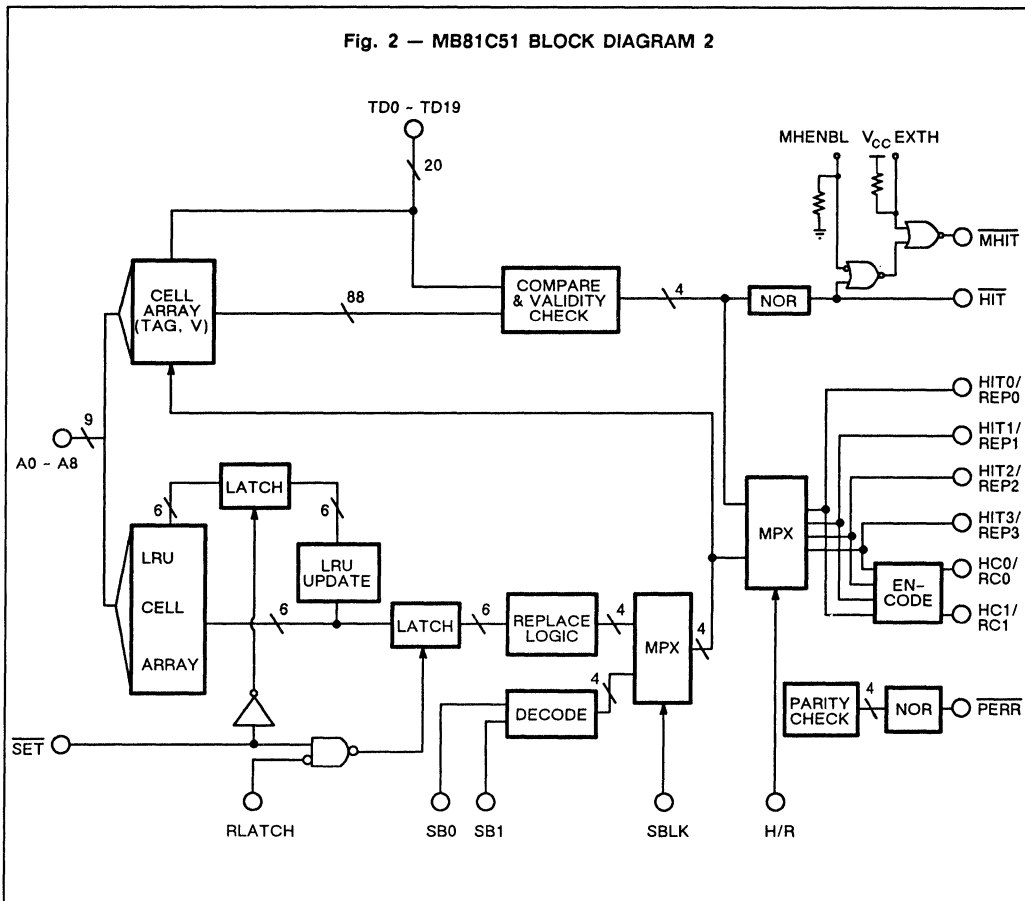
This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields. However, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high impedance circuit.

Fig. 1 — MB81C51 BLOCK DIAGRAM 1



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Fig. 2 — MB81C51 BLOCK DIAGRAM 2



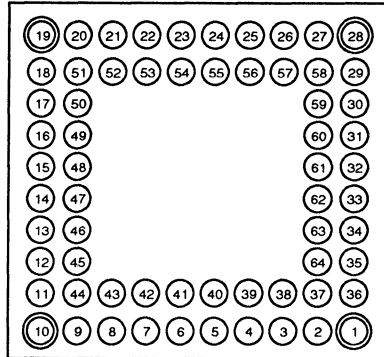
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**CAPACITANCE** (TA = 25°C, f = 1 MHz)

Parameter	Symbol	Typ	Max	Unit
Input Capacitance (VIN = 0V)	CIN		10	pF

PIN ASSIGNMENT

64 PIN PIN GRID ARRAY(PGA-64C-A02)



BOTTOM VIEW

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PIN FUNCTION

Pin No.	Function	Pin No.	Function	Pin No.	Function
1	N.C.	23	A4	45	TD6
2	MHIT	24	A5	46	TD9
3	HIT0/REP0	25	A7	47	Vcc
4	HIT2/REP2	26	A9	48	TD13
5	HIT3/REP3	27	N.C.	49	TD15
6	TD0	28	N.C.	50	TD17
7	TD2	29	PINV	51	TD19
8	EXTH	30	SBLK	52	A0
9	MHENBL	31	SB1	53	A2
10	N.C.	32	INH	54	GND
11	TD7	33	INVL	55	A6
12	TD8	34	SET	56	A8
13	TD10	35	H/R	57	PURGE
14	TD11	36	HIT	58	MODE
15	TD12	37	HC0/RC0	59	VINV
16	TD14	38	HC1/RC1	60	SB0
17	TD16	39	HIT1/REP1	61	Vcc
18	TD18	40	GND	62	WRITE
19	N.C.	41	TD1	63	RLATCH
20	N.C.	42	TD3	64	PERR
21	A1	43	TD4		
22	A3	44	TD5		




## PIN DESCRIPTION

OUTPUTS	
HIT	HIT OUTPUT. "NOR" OF HIT0 TO HIT3
HCn/RCn	CODED OUTPUTS OF HIT OR REPLACE INFORMATION ( n = 0 - 1 )
HITn/REPN	UNCODED OUTPUTS OF HIT OR REPLACE INFORMATION ( n = 0 - 3 )
PERR	PARITY ERROR
MHIT	HIT OUTPUT MODIFIED BY MHENBL AND EXTH
INPUTS	
MODE	MODE SELECTION MODE = 1 : 512 Entry x 4 Way MODE = 0 : 1024 Entry x 2 Way
A0-A9	ADDRESS INPUTS (A9 is not used for 4 way)
TD0-19	TAG INFORMATION INPUTS
PURGE	ALL-PURGE TIMING PULSE
INVL	PARTIAL-PURGE. V-BIT FORCED TO "0". LRU IS REVERSIVELY UPDATED
SBLK	ENABLE WAY-SELECTION EXTERNALLY AT REPLACEMENT AND INVALIDATION
SB0, SB1	EXTERNAL WAY-ADDRESS INPUTS
WRITE	WRITE CYCLE SIGNAL
SET	TIMING PULSE Write : Register TAG, V-bit "H", LRU update Read : LRU updated PARTIAL PURGE : LRU reversively update, V-bit "L"
INH	ALL FUNCTIONS EXCEPT PURGE ARE INHIBITED
H/R	OUTPUT SELECTION H/R = 1 : Hit Information H/R = 0 : Replace Information
RLATCH	LATCH CONTROL FOR REPLACE INFORMATION
PINV	USE FOR "TESTING" ONLY (GENERALLY "H")
VINV	USE FOR "TESTING" ONLY (GENERALLY "H")
MHENBL	ENABLE MHIT OUTPUT
EXTH	FORCE MHIT OUTPUT TO "L"

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## FUNCTION TABLE

### 1) BASIC FUNCTION (Any combination except below are inhibited.)

Input					TAG Info.	Control Info.		LRU	Function Mode
INH	PURGE	SET	WRITE	INVL	TAG	P bit	V bit	LRU	
L	H	X	X	X	N-CNG	N-CNG	N-CNG	N-CNG	INHIBIT <sup>3</sup>
H	H	H	X	X	N-CNG	N-CNG	N-CNG	N-CNG	TAG READ
H	H		H	H	N-CNG	N-CNG	N-CNG	N-CNG <sup>1</sup> or UP-D	TAG READ
H	H		L	H	TD0 to TD19	SET	H	UP-D	TAG WRITE
X	L	H	X	X	UNDEFINED	UNDEFINED	L (All)	INCLZ	ALL PURGE
H	H		H	L	N-CNG	N-CNG	N-CNG/L <sup>2</sup>	N-CNG <sup>1</sup> or RUP-D	PARTIAL PURGE

X : "H" or "L"

N-CNG : No Change

UP-D : Up Dated

RUP-D : Reversively Updated

INCLZ : INITIALIZE

RUP-D : Reversively Updated

1. When SBLK = "L" and no-HIT, then LRU is no change (N-CNG).

2. When SBLK = "L" and no-HIT, then V-Bit is no change (N-CNG).

3. During INHIBIT mode, HIT and PERR outputs are "H" but the other outputs are "L".

## 2) OUTPUT PIN FUNCTION

Input		Internal Info. <sup>1, 2</sup>				Output							Mode	
Mode	A9	hit0/ rep0	hit1/ rep1	hit2/ rep2	hit3/ rep3	HIT0/ REP0	HIT1/ REP1	HIT2/ REP2	HIT3/ REP3	HC0/ RC0	HC1/ RC1	$\frac{3}{\text{HIT}}$		
H	X	L	L	L	L	L	L	L	L	L	L	L	H	4 W A Y
H	X	H	L	L	L	H	L	L	L	L	L	L	L	
H	X	L	H	L	L	L	H	L	L	H	L	L	L	
H	X	L	L	H	L	L	L	H	L	L	H	L	L	
H	X	L	L	L	H	L	L	L	H	H	H	L	L	
L	L	L	X	L	X	L	L	L	L	L	L	L	H	2 W A Y
L	L	H	X	L	X	H	L	L	L	L	L	L	L	
L	L	L	X	H	X	L	L	H	L	L	H	L	L	
L	H	X	L	X	L	L	L	L	L	L	L	L	H	
L	H	X	H	X	L	L	H	L	L	H	L	L	L	
L	H	X	L	X	H	L	L	L	H	H	H	L	L	

X: "H" or "L"

1. Internal information, rep0 to rep3 are determined by on-chip LRU logic when SBLK = "L". When SBLK = "H", the internal information are determined by external signal of SB0 & SB1.
2. Correct operation is not guaranteed if 2 ways or more become HIT at the same time.
3. Output of HIT is valid when H/R = "H".

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## 3) PARTIAL PURGE ( $\overline{\text{INVL}} = \text{"L"}\text{"}$ )

INPUT					INTERNAL INFO.				PURGE BLOCK				SET	MODE
MODE	A9	SBLK	SB0	SB1	HIT				BLOCK				LRU	
					0	1	2	3	0	1	2	3		
H	X	L	X	X	L	L	L	L	—	—	—	—	---	4 W A Y
H	X	L	X	X	H	L	L	L	Q	—	—	—	RUP-D	
H	X	L	X	X	L	H	L	L	—	Q	—	—	RUP-D	
H	X	L	X	X	L	L	H	L	—	—	Q	—	RUP-D	
H	X	L	X	X	L	L	L	H	—	—	—	Q	RUP-D	
H	X	H	L	L	X	X	X	X	Q	—	—	—	RUP-D	
H	X	H	H	L	X	X	X	X	—	Q	—	—	RUP-D	
H	X	H	H	H	X	X	X	X	—	—	—	Q	RUP-D	
L	L	L	X	X	L	X	L	X	—	—	—	—	---	
L	L	L	X	X	H	X	L	X	Q	—	—	—	RUP-D	2 W A Y
L	L	L	X	X	L	X	H	X	—	—	Q	—	RUP-D	
L	L	H	L	L	X	X	X	X	Q	—	—	—	RUP-D	
L	L	H	L	H	X	X	X	X	—	—	Q	—	RUP-D	
L	H	L	X	X	X	L	X	L	—	—	—	—	---	
L	H	L	X	X	X	H	X	L	—	Q	—	—	RUP-D	
L	H	L	X	X	X	L	X	H	—	—	—	Q	RUP-D	
L	H	H	H	L	X	X	X	X	—	Q	—	—	RUP-D	
L	H	H	H	H	X	X	X	X	—	—	—	Q	RUP-D	

Note: Correct operation is not guaranteed if 2 ways or more become HIT at the same time.

#### 4) PARITY ERROR & V-BIT<sup>1</sup> (n : 0 to 3)

pen	vn0	vn1	PEn	HIT Info. <sup>2</sup>
L	L	L	L	---
L	L	H	H	HIT
L	H	L	H	HIT
L	H	H	L	HIT
H	L	L	L	---
H	L	H	H	HIT
H	H	L	H	HIT
H	H	H	H	HIT

pen : Internal parity error of way "n"  
vn0/vn1 : Duplicate validity bits.  
PEn : Determined by the following equation.

$$PEn = (vn0 + vn1) \cdot pen + (vn0 \oplus vn1)$$

1. PERR is "NOR" of PE0 to PE3
2. Output information when internal "HIT" is valid.

## BASIC FUNCTIONS

### TAG READ

A comparison between the TAG Input data (TD0-19) and the contents of the addressed location is performed. If both data are the same, that is "FOUND". Then HIT will be "LOW" and outputs of HCN, HITn indicate hit "Associative way". In the case of "NOT-FOUND", the TAG RAM will specify the "way", which should be replaced, by using the LRU logic automatically.

The replacement information will be presented at the outputs of RCn and REPn by forcing the H/R Input into "LOW". These signals will be latched and used for the data Memory move-in operation.

### TAG WRITE

When "NOT-FOUND" is occurred, the TAG-RAM also should be updated. The write operation is performed by WRITE "LOW" and SET pulse input. The TAG data will be written into the proper "way" by the internal LRU logic.

TAG-WRITE mode, V-bit (Validity bit) and the parity are set, and LRU logic is updated.

On the other hand, it will be able to specify the "way" externally by using SBLK, SB0 and SB1 inputs.

### ALL PURGE

By asserting PURGE input "LOW", the V-bit are reset and LRU logic is initialized.

In this operation, the contents of each TAG and its parity will not be identified.

### PARTIAL PURGE

The partial purge operation is performed by INV L "LOW" and SET pulse input.

The V-bit, which is specified by the address inputs, will be reset, and LRU logic will be reversively updated.

## RECOMMENDED OPERATING CONDITIONS (Referenced to GND)

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V <sub>CC</sub>	4.5	5.0	5.5	V
Ambient Temperature	T <sub>A</sub>	0		70	°C

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## DC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

Parameter	Test Condition	Symbol	Min	Max	Unit
Input Leakage Current	V <sub>IN</sub> = 0 V to V <sub>CC</sub>	I <sub>LI</sub>	-10	10	μA
Operating Supply Current	DOUT = Open, Cycle = min.	I <sub>CC</sub>		250	mA
Input Low Voltage		V <sub>IL</sub>	-0.5*	0.8	V
Input High Voltage		V <sub>IH</sub>	2.2	6.0	V
Output Low Voltage	I <sub>OL</sub> = 8mA	V <sub>OL</sub>		0.4	V
Output High Voltage	I <sub>OH</sub> = -4mA	V <sub>OH</sub>	2.4		V

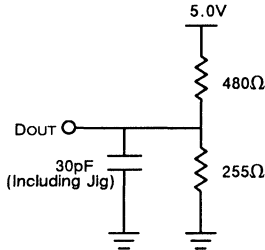
Note:

\*-3.0V min. for pulse width less than 20ns.



Fig. 3 – AC TEST CONDITION

INPUT PULSE LEVELS : 0.0V to 3.0V  
 INPUT PULSE RISE AND FALL TIMES: 5ns (Transient time between 0.8V and 2.2V)  
 TIMING REFERENCE LEVELS : Input : 1.5V  
 Output : 1.5V  
 OUTPUT LOAD:



## AC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

TAG READ CYCLE (MODE = "H" or "L", PURGE = "H", WRITE = "H", INVL = "H", PINV = "H", or "L", VINV = "H" or "L", INH = "H")

Parameter	Symbol	MB81C51-25		MB81C51-30		Unit
		Min	Max	Min	Max	
Read Cycle Time	t <sub>RC</sub>	50		50		ns
Address Valid to $\overline{\text{HIT}}$ , HC <sub>n</sub> , HIT <sub>n</sub>	t <sub>AH</sub>		25		30	ns
Address Valid to $\overline{\text{MHIT}}$	t <sub>AMH</sub>		27		32	ns
TAG Data Valid to $\overline{\text{HIT}}$ , HC <sub>n</sub> , HIT <sub>n</sub>	t <sub>TH</sub>		18		18	ns
TAG Data Valid to $\overline{\text{MHIT}}$	t <sub>TMH</sub>		20		20	ns
$\overline{\text{HIT}}$ , HC <sub>n</sub> , HIT <sub>n</sub> Hold Time	t <sub>HH</sub>	0		0		ns
Address Valid to RC <sub>n</sub> , REP <sub>n</sub>	t <sub>AR</sub>		35		40	ns
Address Valid to $\overline{\text{PERR}}$	t <sub>AP</sub>		35		40	ns
Address Setup Time for $\overline{\text{SET}}$	t <sub>AS</sub>	25		25		ns
TAG Data Setup Time for $\overline{\text{SET}}$	t <sub>TS</sub>	25		25		ns
$\overline{\text{SET}}$ Pulse Width	t <sub>SW</sub>	20		20		ns
$\overline{\text{SET}}$ Recovery Time	t <sub>SR</sub>	5		5		ns
RLATCH Setup Time	t <sub>RLS</sub>	10		10		ns
RC <sub>n</sub> , REP <sub>n</sub> Hold Time for RLATCH	t <sub>RH</sub>	0		0		ns
SBLK, SB0, SB1 Setup Time for RC <sub>n</sub> , REP <sub>n</sub>	t <sub>SBR</sub>		25		25	ns
SBLK, SB0, SB1 Hold Time	t <sub>SBH</sub>	5		5		ns
RC <sub>n</sub> , REP <sub>n</sub> Hold Time for SBLK, SB0, SB1	t <sub>SH</sub>	0		0		ns
SBLK, SB0, SB1 Setup Time for $\overline{\text{SET}}$	t <sub>SBS</sub>	25		25		ns
$\overline{\text{PERR}}$ Hold Time	t <sub>PH</sub>	0		0		ns
H/R to Multiplex output change	t <sub>HR</sub>		10		12	ns
MHENBL, EXTH to $\overline{\text{MHIT}}$ output	t <sub>MMH</sub>		10		12	ns

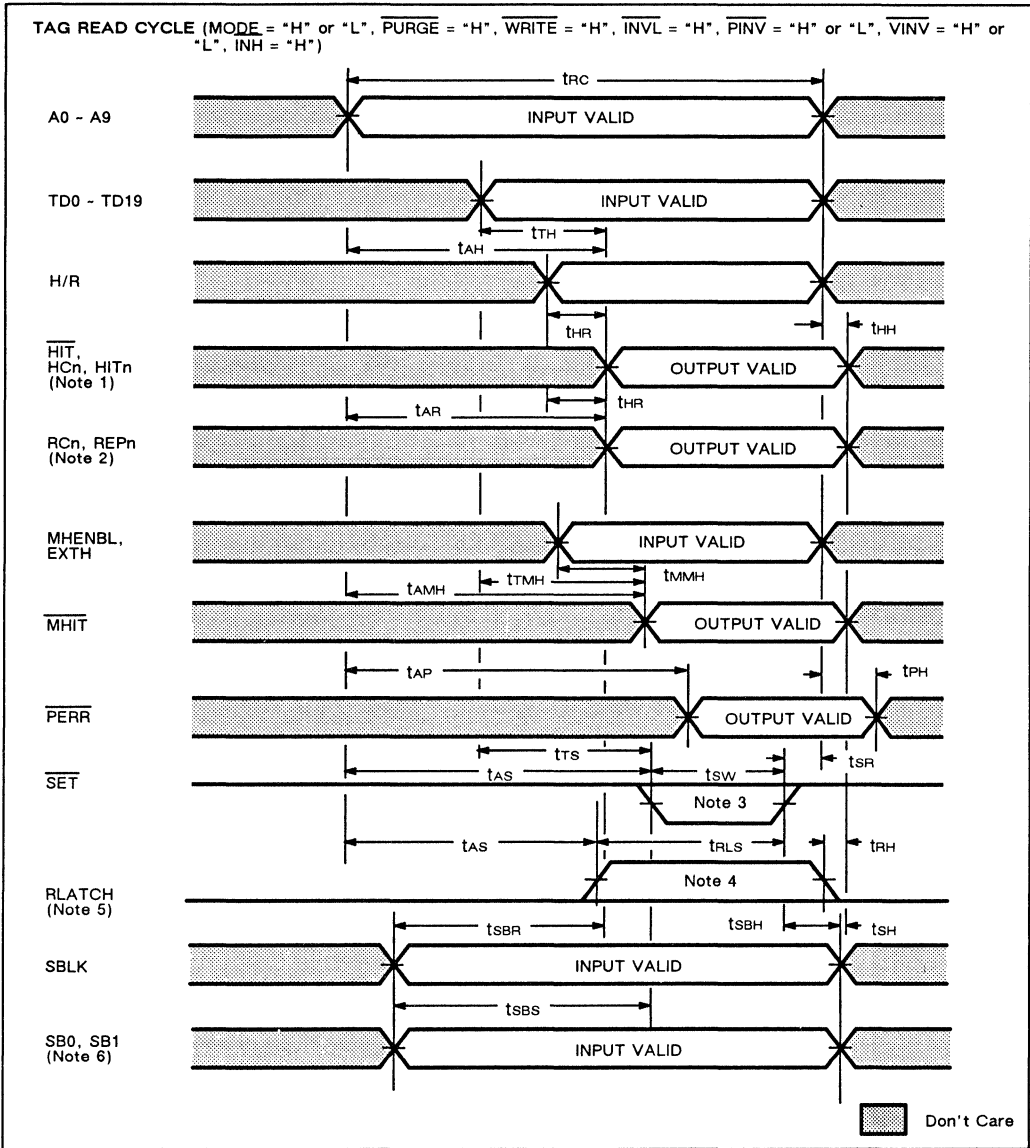
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MB81C51-30

TAG WRITE CYCLE (MODE = "H" or "L", PURGE = "H", WRITE = "L", INVL = "H", H/R = "L", INH = "H")						
Parameter	Symbol	MB81C51-25		MB81C51-30		Unit
		Min	Max	Min	Max	
Write Cycle Time	tWC	50		50		ns
Address Valid to RC <sub>n</sub> , REP <sub>n</sub>	tAR		35		40	ns
Address Setup Time for $\overline{\text{SET}}$	tAS	25		25		ns
TAG Data Setup Time for $\overline{\text{SET}}$	tTS	25		25		ns
$\overline{\text{SET}}$ Pulse Width	tSW	20		20		ns
$\overline{\text{SET}}$ Recovery Time	tSR	5		5		ns
RLATCH Setup Time	tRLS	10		10		ns
SBLK, SB0, SB1 Setup Time for $\overline{\text{SET}}$	tsBS	25		25		ns
SBLK, SB0, SB1 Setup Time for PC <sub>n</sub> , REP <sub>n</sub>	tsBR		25		25	ns
PC <sub>n</sub> , REP <sub>n</sub> Hold Time for SBLK, SB0, SB1	tSH	0		0		ns
SBLK Hold Time	tsBH	5		5		ns
PINV, $\overline{\text{VINV}}$ Setup Time for $\overline{\text{SET}}$	tIS	25		25		ns
PINV, $\overline{\text{VINV}}$ Hold Time	tIR	5		5		ns

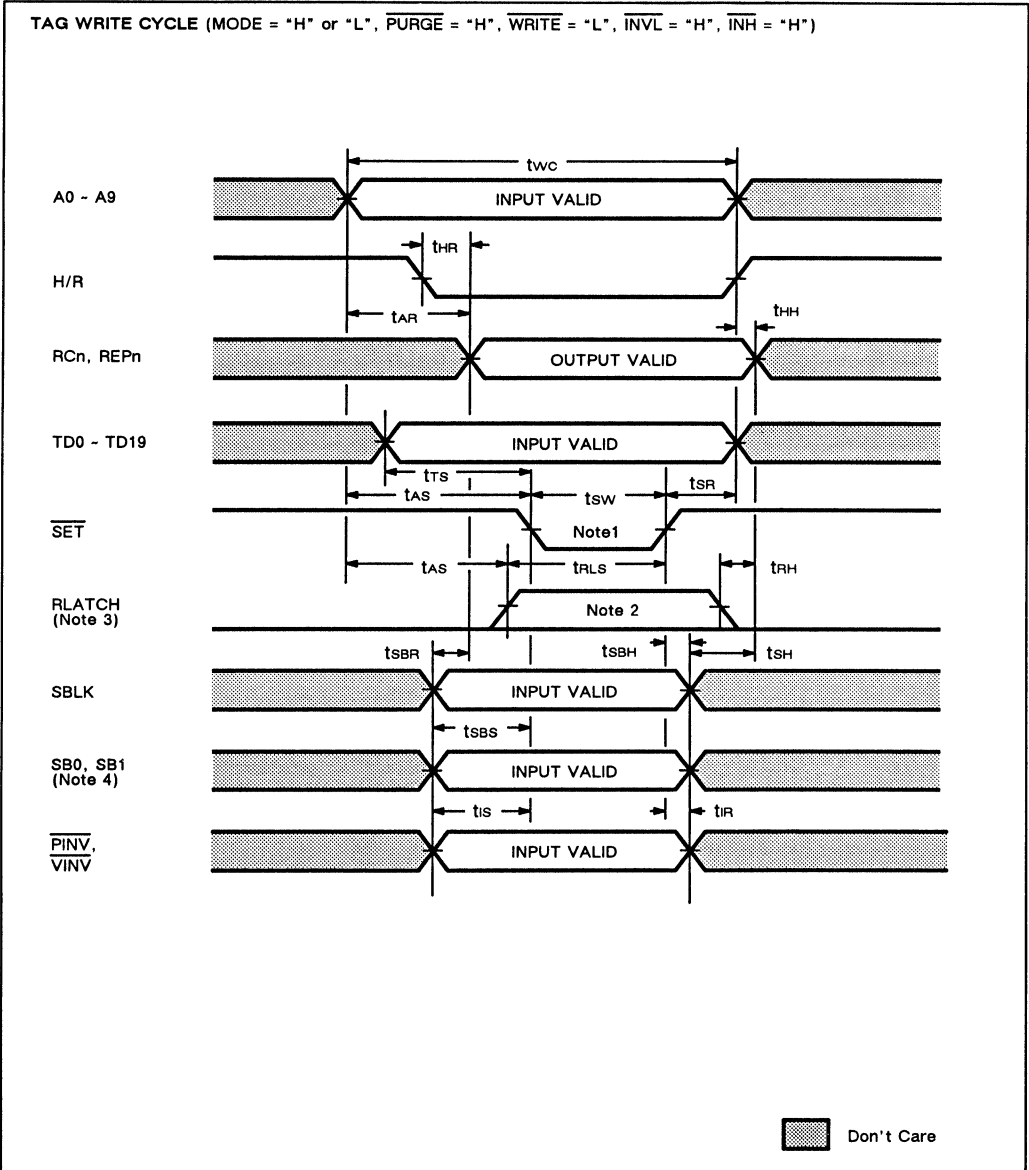
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PARTIAL PURGE (MODE = "H" or "L", PURGE = "H", WRITE = "H", INVL = "L", H/R = "H" or "L", INH = "H", RLATCH = "L", PINV = "H" or "L", $\overline{\text{VINV}}$ = "H" or "L")						
Parameter	Symbol	MB81C51-25		MB81C51-30		Unit
		Min	Max	Min	Max	
Partial Purge Cycle	tPPC	50		50		ns
Address Setup Time for $\overline{\text{SET}}$	tAS	25		25		ns
TAG Data Setup Time for $\overline{\text{SET}}$	tTS	25		25		ns
$\overline{\text{SET}}$ Pulse Width	tSW	20		20		ns
$\overline{\text{SET}}$ Recovery Time	tSR	5		5		ns
SBLK, SB0, SB1 Setup Time for $\overline{\text{SET}}$	tsBS	25		25		ns
SBLK, SB0, SB1 Hold Time	tsBH	5		5		ns

ALL PURGE ( $\overline{\text{SET}}$ = "H", Other control inputs are "H" or "L")						
Parameter	Symbol	MB81C51-25		MB81C51-30		Unit
		Min	Max	Min	Max	
All Purge Cycle Time	tAPC	100		100		ns
Purge Pulse Width	tPPW	50		50		ns
Purge Recovery Time	tPR	50		50		ns

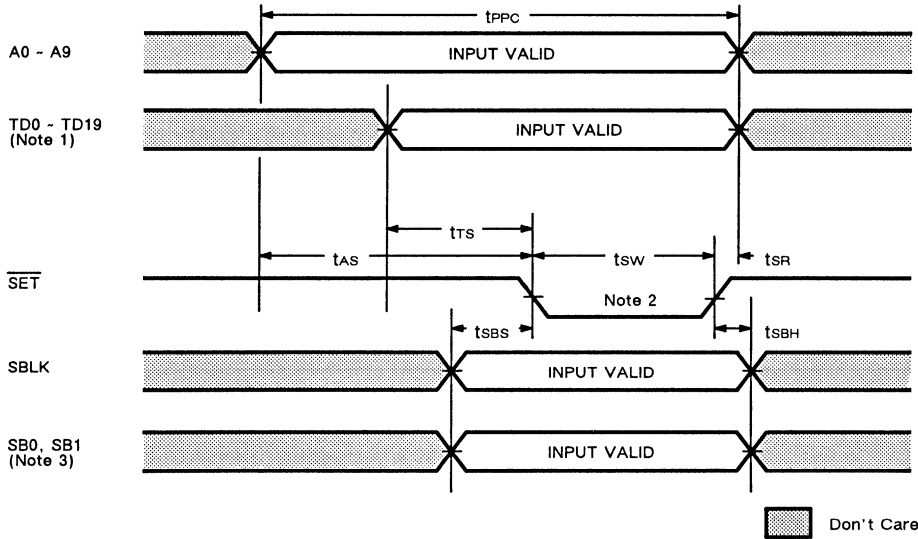


- Notes 1: Valid at H/R = "H".  
 2: Valid at H/R = "L".  
 3: LRU is updated at SET = "L".  
 4: Replace latched at RLATCH = "H".  
 5: Valid at SBLK = "L".  
 6: Valid at SBLK = "H".



- Notes 1. Register TAG, V-bit "H", LRU update.  
 2. Replace latched at RLATCH = "H".  
 3. Valid at SBLK = "L".  
 4. Valid at SBLK = "H".

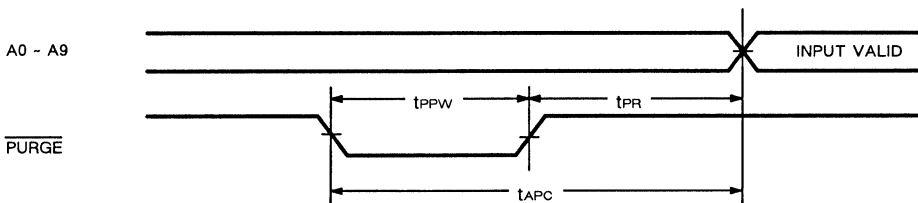
PARTIAL PURGE CYCLE (MODE = "H" or "L",  $\overline{\text{PURGE}}$  = "H",  $\overline{\text{WRITE}}$  = "H",  $\overline{\text{INVL}}$  = "L", H/R = "H" or "L",  $\overline{\text{INH}}$  = "H",  
RLATCH = "L",  $\overline{\text{PINV}}$  = "H" or "L",  $\overline{\text{VINV}}$  = "H" or "L")



Notes:

1. Valid at SBLK = "L".
2. LRU is reversively updated, V-bit "L".
3. Valid at SBLK = "H".

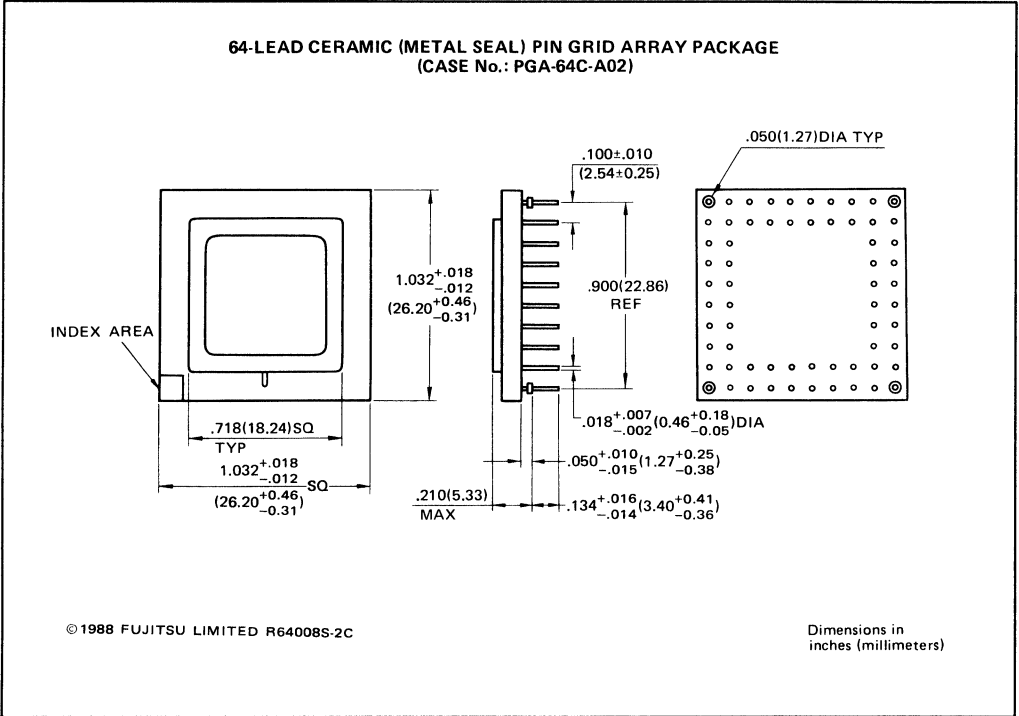
All purge ( $\overline{\text{SET}}$  = "H", OTHER CONTROL INPUTS ARE "H" or "L")



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MB81C51-30

# PACKAGE DIMENSIONS

(Suffix: -CR)



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